

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant:	Georg Muller	)	Confirmation No.: 1586
		)	
Serial No.:	10/663,448	)	Group Art Unit: 2858; 2829
U.S. Patent No.:	7,126,326 B2	)	
		)	
Filed:	16 September 2003	)	Examiner: CHAN, Emily Y.
		)	

Title SEMICONDUCTOR DEVICE TESTING APPARATUS, SEMICONDUCTOR DEVICE TESTING SYSTEM, AND SEMICONDUCTOR DEVICE TESTING METHOD FOR MEASURING AND TRIMMING THE OUTPUT IMPEDANCE OF DRIVER DEVICES

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**REQUEST FOR STATUS OF PETITION**

Sir:

This is a Request for the STATUS of the Petition Under 37 CFR 1.181(a) and 35 U.S.C. § 254 for Correction of Mistake in a Patent, Incurred Through the Fault of the Patent and Trademark Office, the Petition filed on February 16, 2007.

Respectfully submitted,

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